

## C0805C222K2GECTU

Aliases (C0805C222K2GEC7800)

ESD SMD Comm COG, Ceramic, 2,200 pF, 10%, 200 VDC, COG, SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I, 0805, 0.7



General Information	
Series	ESD SMD Comm COG
Style	SMD Chip
Description	SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I
Features	Temperature Stable, Low ESR, Class I
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	11 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	0805
L	2mm +/-0.2mm
W	1.25mm +/-0.2mm
Т	0.78mm +/-0.10mm
S	0.7mm MIN
В	0.5mm +/-0.25mm

1	0.78mm +/-0.10mm	Voltage DC	200 VDC
S	0.7mm MIN	ESD Level per AEC-Q200	12,000 V ESD Leve
В	0.5mm +/-0.25mm	Dielectric Withstanding Voltage	500 VDC
		Temperature Range	-55/+125°C
Packaging Specifications		Temp. Coefficient	COG
Packaging	T&R, 180mm, Paper Tape	Capacitance Change with 30 ppm/C, 1kHz	30 ppm/C, 1kHz 1.0
Packaging Quantity	4000	Reference to +25°C and 0 VDC Applied (TCC)	

Specifications	
Capacitance	2,200 pF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	10%
Voltage DC	200 VDC
ESD Level per AEC-Q200	12,000 V ESD Level
Dielectric Withstanding Voltage	500 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	COG
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms
Dissipation Factor	0.1% 1 kHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour
Insulation Resistance	100 GOhms

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